WMSC040S12B1P

N-Channel Silicon Carbide MOSFET Module

Rev.02 - 24 September 2024

Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and Press-fit pin type. NTC temperature sensor inside.



2. Features and benefits

- · 3-phase full bridge topology
- Press-fit pin configuration
- Low ON resistance
- Low switching losses
- Reduced Q_g and C_{rss}
- Minimized circuit impedance
- Robust product design

3. Applications

- · EV chargers
- Energy storage and solar energy systems
- Power Inverters
- AC/DC converters
- Power factor correctors
- Motor drives

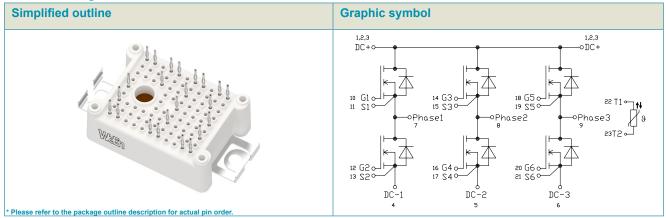
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values			Unit		
Absolute maximum rating									
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V		
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			37		А		
P _{tot}	total power dissipation	T _h = 25 °C			74		W		
T _{j.op}	maximum junction temperature				-40 to 15	60	°C		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit		
Static cha	aracteristics								
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 33 \text{ A}; T_j = 25 \text{ °C}$		-	40	-	mΩ		
		V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ		
Dynamic	characteristics								
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	116	-	nC		
Q_{GD}	gate-drain charge	T _j = 25 °C		-	19	-	nC		
Source-drain diode									
Q _r	recovered charge	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt = 2700 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_{j} = 25 °C		-	707	-	nC		

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
WMSC040S12B1P	WeEnPACK-B1	WMSC040S12B1P6T	Tray	_	WeEnPACK- B1PSB-B	13-Jun-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040S12B1P	WMSC040S12B1P

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T _{stg}	storage temperature			-40 to 125	°C
$T_{j.op}$	operating junction temperature			-40 to 150	°C
$T_{j.max}$	maximum junction temperature	Intermittent condition with shortened lifetime		-40 to 175	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET					
V _{DS}	drain-source voltage	T _j = 25 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		74	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		37	Α
		V _{GS} = 18 V; T _h = 100 °C		23	Α
I _{DM}	peak drain current	pulse width t_p limited by T_{jmax}		74	Α
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 24 A; L = 1 mH; V_{DD} = 100 V; $T_{j(init)}$ = 25 °C; per MOSFET		288	mJ
Body Diod	de				
I _{SD}	DC body diode forward current	V _{GS} = -4 V; T _h = 25 °C		15	Α
I _{SD,pulse}	Pulse body diode current	verified by design, $t_{\scriptscriptstyle p}$ limited by $T_{\scriptscriptstyle jmax}$		74	А

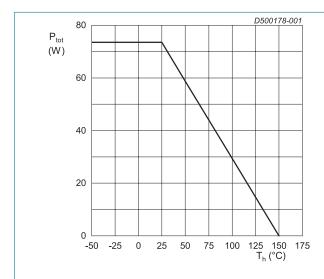


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

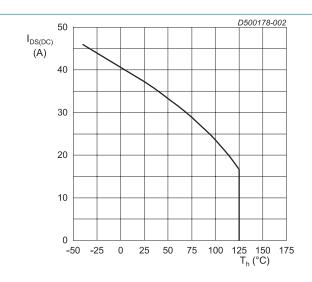


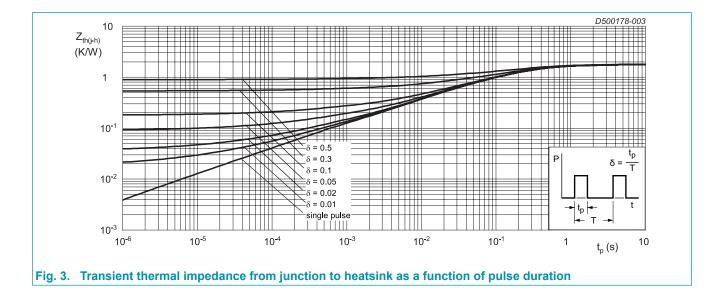
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
$R_{\text{th(j-c)}}$	thermal resistance from junction to case	per MOSFET		-	0.7	-	K/W
$R_{\text{th(j-h)}}$	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 1 \text{ W/(m·K)}$, thick _{grease} = 50 um		-	1.7	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al_2O_3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index				>200		
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommended.



10. Characteristics

Table 7. Characteristics

MOSFET	Darameter	Conditions	Notes	Min	Tyrn	Mov	Unit
Symbol Statio ob	Parameter	Conditions	Notes	Min	Тур	Max	Unit
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 100 \ \mu A; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^{\circ}C$		1200	-	-	V
$V_{GS(th)}$	gate-source threshold	$I_D = 10 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$		1.9	2.5	3.5	V
	voltage	I _D = 10 mA; V _{DS} = V _{GS} ; T _j = 175 °C		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.2	100	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 125 °C		-	45	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 150 °C		-	53	-	mΩ
	V _{GS} = 18 V; I _D = 33 A; T _j = 175 °C		-	55.7	-	mΩ	
R _G	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	0.8	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 33 A; T _j = 25 °C		-	27	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	116	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	42	-	nC
Q_{GD}	gate-drain charge			-	19	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 1 MHz;		-	2450	-	pF
C _{oss}	output capacitance	T _j = 25 °C		-	108	-	pF
C _{rss}	reverse transfer capacitance			-	11	-	pF
E _{oss}	Coss stored energy			-	54	-	μJ
$t_{d(on)}$	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	17	-	ns
t _r	rise time	$R_{G(off)} = 5.1 \Omega; R_{G(on)} = 5.1 \Omega;$ $I_D = 33 A; L = 300 \mu H; T_i = 25 °C$		-	10	-	ns
$t_{d(off)}$	turn-off delay time			-	42	-	ns
t _f	fall time			-	14	-	ns
E _{on}	turn-on energy			-	492	-	μJ
E _{off}	turn-off energy			-	124	-	μJ

Body dio	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V; } I_{SD} = 33 \text{ A; } T_j = 25 \text{ °C}$		-	5.5	-	V
		$V_{GS} = -4 \text{ V; } I_{SD} = 33 \text{ A; } T_j = 150 ^{\circ}\text{C}$		-	5.0	-	V
Dynamic	characteristics				'		
I _{rrm}	reverse recovery current	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V;		-	50	-	А
t _{rr}	reverse recovery time	di/dt = 2700 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	24	-	ns
Q _r	recovered charge	ı		-	707	-	nC
E _{rec}	reverse recovery energy			-	91	-	μJ
I _{rrm}	reverse recovery current	$I_{SD} = 33 \text{ A}; V_{GS} = -4 \text{ V}/18 \text{ V}; V_{R} = 600 \text{ V};$		-	66	-	Α
t _{rr}	reverse recovery time	di/dt = 3600 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 150 °C		-	25	-	ns
Q _r	recovered charge	J		-	1032	-	nC
E _{rec}	reverse recovery energy			-	138	-	μJ
NTC ther	mistor				•		
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C		493±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/l
	Thermal time constant			-	≤10	-	s

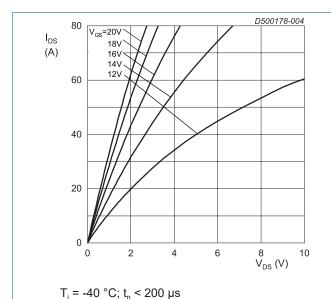
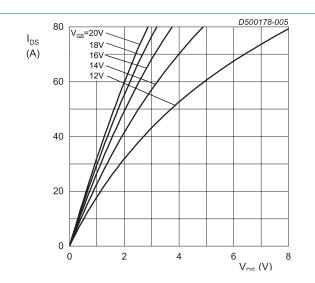
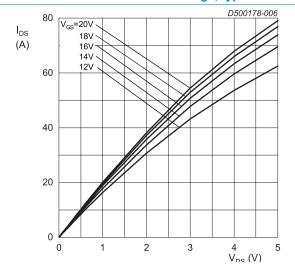


Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

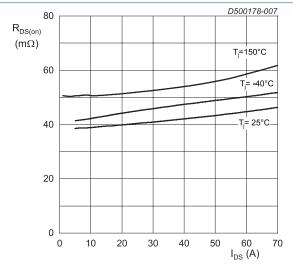


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values

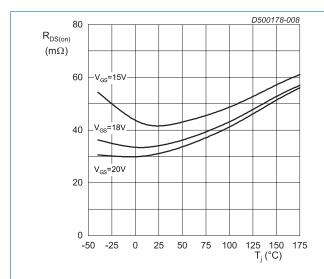


T_j = 150 °C; t_p < 200 μs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values



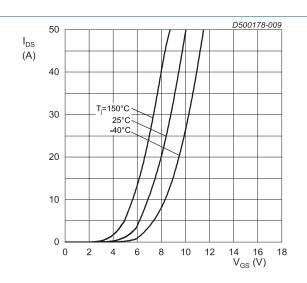
 $V_{GS} = 18 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



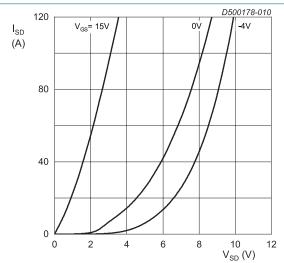
 I_{DS} = 33 A; t_p < 200 μ s

Fig. 8. Drain-source on-state resistance as a function of junction temperature

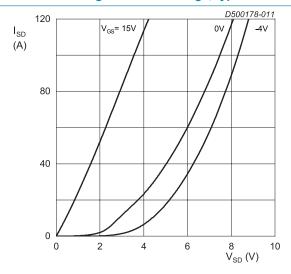


 V_{DS} = 20 V; t_p < 200 μs

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values

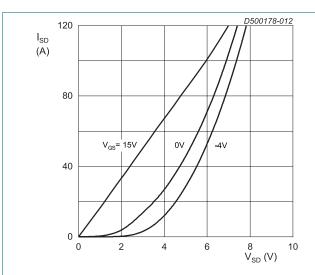


 T_j = -40 °C; t_p < 200 µs Fig. 10. Body diode forward characteristics; typical values



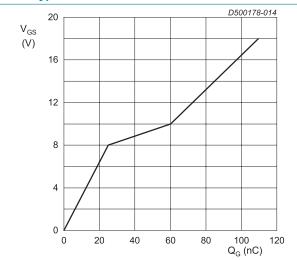
 T_j = 25 °C; t_p < 200 μ s

Fig. 11. Body diode forward characteristics; typical values

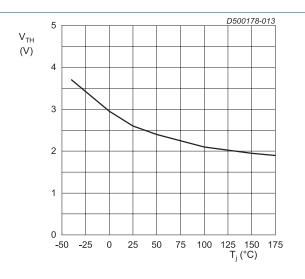


 T_j = 150 °C; t_p < 200 µs

Fig. 12. Body diode forward characteristics; typical values



 I_{DS} = 33A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values



V_{DS} = V_{GS}; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature

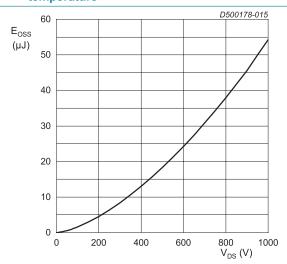
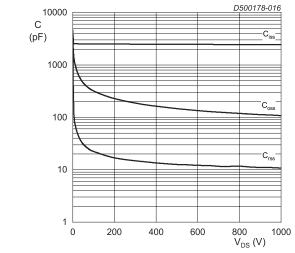
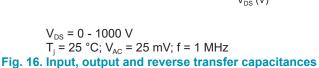
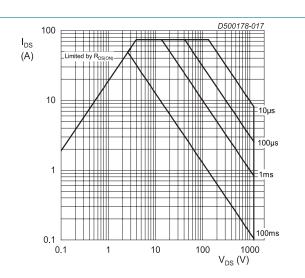


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



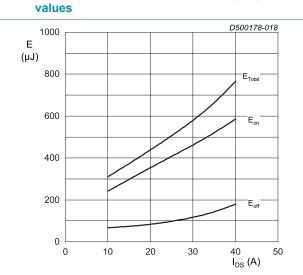


as a function of drain-source voltage; typical



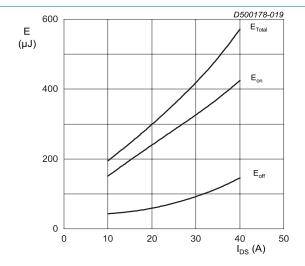
 $T_j = 25$ °C; D = 0 Parameter: t_p

Fig. 17. Forward bias safe operating area



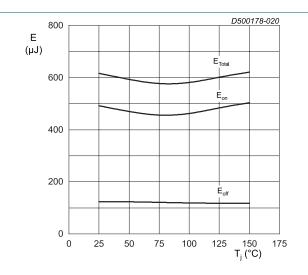
 $T_j = 25$ °C; $V_{DD} = 800$ V; $R_{G(off)} = 5.1$ Ω ; $R_{G(on)} = 5.1$ Ω ; $V_{GS} = -4$ V/18 V; L = 300 μ M

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



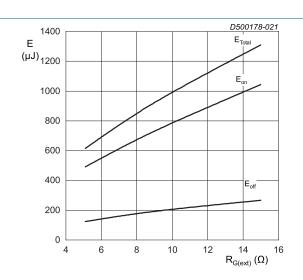
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



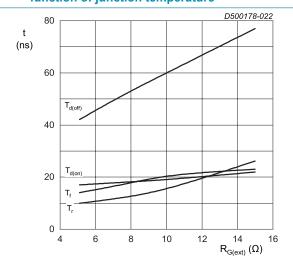
 I_{DS} = 33 A; V_{DD} = 800 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 300 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 33 A; $V_{\rm GS}$ = -4 V/18 V; L = 300 μH

Fig. 22. Switching time as a function of external gate resistance

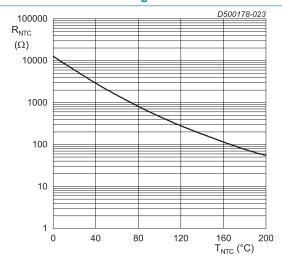
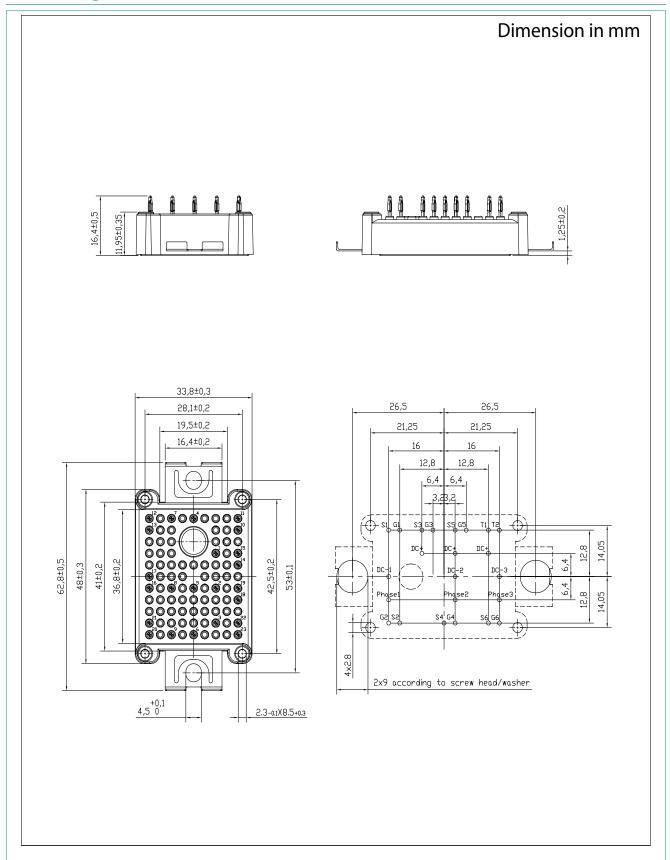


Fig. 23. NTC thermistor resistance as a function of NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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13. Contents

1. General description	1
2. Features and benefits	1
3. Applications	1
4. Quick reference data	1
5. Pinning information	2
6. Ordering information	2
7. Ordering information	2
8. Limiting values	3
9. Thermal characteristics	4
10. Characteristics	5
11. Package outline	12
12. Legal information	13
13. Contents	15

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Date of release: 24 September 2024

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